

## ABSTRACT OF THE DISCLOSURE

A defect inspection system according to the present invention comprises image acquiring section for acquiring a two-dimensional image of a subject which is a processing target in a manufacturing process, defect extracting section for extracting a defect by a defect extraction algorithm using a predetermined parameter for an image acquired by the image acquiring section, displaying section for displaying an image of a defect of the subject extracted by the defect extracting section, parameter adjusting section for adjusting the parameter in accordance with a defect extraction degree for the subject, and quality judging section for judging the quality of the subject based on a defect information extracted by the defect extracting section.

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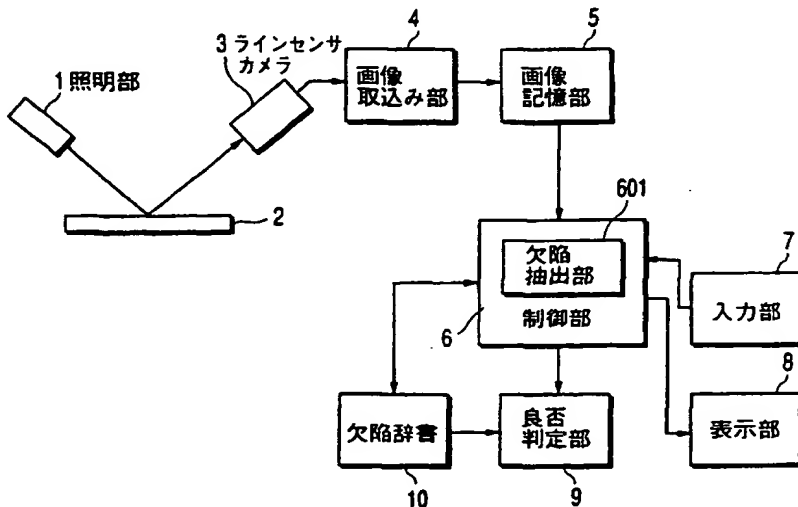
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(54) Title: DEFECT INSPECTING SYSTEM

(54) 発明の名称: 欠陥検査システム



(57) Abstract: A defect inspecting system comprising image capturing means for capturing a two-dimensional image of an object to be processed in a manufacturing process, defect extracting means for extracting a defect from the captured image according to a defect extracting algorithm using a predetermined parameter, display means for displaying the image of the defect of the object extracted, parameter adjusting means for adjusting the parameter according to the degree of extraction of the defect of the object, and acceptance/rejection judging means for judging whether or not the object is acceptable according to the information on the extracted defect.

- 1...ILLUMINATING UNIT  
3...LINE SENSOR CAMERA  
4...IMAGE CAPTURING UNIT  
5...IMAGE STORAGE UNIT  
601...DEFECT EXTRACTING SECTION  
6...CONTROL UNIT  
7...INPUT UNIT  
10...DEFECT DICTIONARY  
9...ACCEPTANCE/REJECTION JUDGING UNIT  
8...DISPLAY UNIT

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